

PCN Number:	20180628002.1	PCN Date:	July 3, 2018
Title:	Qualification of MIHO8 as an additional Fab site option for select ABCD5HV devices		
Customer Contact:	PCN Manager	Dept:	Quality Services
Proposed 1st Ship Date:	Oct 3, 2018	Estimated Sample Availability:	Date provided at sample request.
Change Type:			
<input type="checkbox"/> Assembly Site	<input type="checkbox"/> Assembly Process	<input type="checkbox"/> Assembly Materials	
<input type="checkbox"/> Design	<input type="checkbox"/> Electrical Specification	<input type="checkbox"/> Mechanical Specification	
<input type="checkbox"/> Test Site	<input type="checkbox"/> Packing/Shipping/Labeling	<input type="checkbox"/> Test Process	
<input type="checkbox"/> Wafer Bump Site	<input type="checkbox"/> Wafer Bump Material	<input type="checkbox"/> Wafer Bump Process	
<input checked="" type="checkbox"/> Wafer Fab Site	<input type="checkbox"/> Wafer Fab Materials	<input type="checkbox"/> Wafer Fab Process	
	<input type="checkbox"/> Part number change		

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of its MIHO8 fabrication facility as an additional Wafer Fab source for the selected devices listed in the "Product Affected" section.

Current Fab Site			Additional Fab Site		
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter
MAINEFAB	ABCD5HV	200 mm	MIHO8	ABCD5HV	200 mm

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current:

Current Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
MAINEFAB	CUA	USA	South Portland

New Fab Site:

New Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
MIHO8	MH8	JPN	Ibaraki

Sample product shipping label (not actual product label)

 TEXAS INSTRUMENTS

MADE IN: Malaysia
2DC: 20:

MSL 2 / 260C / 1 YEAR	SEAL DT
MSL 1 / 235C / UNLIM	03/29/04

OPT:
ITEM: 39
LBL: 5A (L)T0:1750



(1P) SN74LS07NSR
(Q) 2000 (D) 0336
(31T) LOT: 3959047MLA
(4W) TKY (1T) 7523483S12
(P)
(2P) REV: (V) 0033317
(20L) CSO: SHE (21L) CCO: USA
(22L) ASO: MLA (23L) ACO: MYS

Product Affected:

TCAN1042HD	TCAN1042HGVD	TCAN1051HD	TCAN1051HGVD
TCAN1042HDR	TCAN1042HGVD R	TCAN1051HDR	TCAN1051HGVD R
TCAN1042HGD	TCAN1042HVD	TCAN1051HGD	TCAN1051HVD
TCAN1042HGDR	TCAN1042HVDR	TCAN1051HGDR	TCAN1051HVDR

Qualification Report

ABCD05HV in Miho8 Approve Date 23-Jun-2018

Product Attributes

Attributes	Qual Device: TCAN1042HVDRQ1	Qual Device: TCAN1051VDRQ1
Assembly Site	FMX	FMX
Package Family	SOIC	SOIC
Flammability Rating	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	MIHO8	MIHO8
Wafer Fab Process	ABCD05HV.3	ABCD05HV.3

- QBS: Qual By Similarity

- Qual Devices TCAN1042HVDRQ1 and TCAN1051VDRQ1 are qualified at LEVEL1-260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: TCAN1042HVDRQ1	Qual Device: TCAN1051VDRQ1
AC	Autoclave 121C	96 Hours	2/154/0	1/77/0
CDM	ESD - CDM	1500 V	2/6/0	1/3/0
ED	Electrical Distributions	Per Datasheet Parameters	3/90/0	3/90/0
ELFR	Early Life Failure Rate, 125C	48 Hours	2/1600/0	1/800/0
HAST	Biased HAST, 130C/85%RH	96 Hours	2/154/0	1/77/0
HBM	ESD - HBM	6000 V	1/3/0	1/3/0
HBM	ESD - HBM (Bus Pins Only)	16000 V	2/6/0	1/3/0
HTOL	Life Test, 150C	300 Hours	2/153/0	1/77/0
HTSL	High Temp Storage Bake 175C	500 Hours	2/90/0	1/45/0
LU	Latch-up	(Per JESD78)	2/12/0	1/6/0
TC	Temperature Cycle, -65/150C	500 Cycles	2/154/0	1/77/0
WBP	Bond Pull	Wires	2/60/0	-
WBS	Wire Bond Shear	Wires	2/60/0	1/30/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

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